Reg. No.							*	
2108.7.101								

## **B.Tech. DEGREE EXAMINATION, NOVEMBER 2023**

Fourth Semester

## 18ECE321T - RF AND MICROWAVE SEMICONDUCTOR DEVICES

(For the candidates admitted from the academic year 2020-2021 to 2021-2022)

7	N. T			
	-	01	tο	4

(i) Part - A should be answered in OMR sheet within first 40 minutes and OMR sheet should be handed over to hall invigilator at the end of 40<sup>th</sup> minute.

(ii)	Part - B & Part - C should be answered							
Time: 3 hours		Max. Marks: 100						
	$PART - A (20 \times 1)$	= 20 1	Marke)	Marks	BL	со	PO	
	Answer ALL (							
1	In a PN junction, with no external vo			r 1	1	1	1	
1.	and donor ions is called	nage,	me electric held between acceptor					
		(D)	Peak					
	(A) Threshold	` /	Barrier					
	(C) Path	(D)	Darrier					
2.	Schottky diode operates only with			1	1	1	1	
	(A) Minority carriers	(B)	Capacitor	•				
	(C) Inductor	(D)	Majority carriers					
	` ′							
3.	The varactor is usually			1	1	1		
	(A) Forward biased	(B)	Unbiased					
	(C) Reverse biased	(D)	In the breakdown region					
4.	The PIN diode is most suited for		applications.	1	1	1	1	
	(A) Microwave switching	(B)	Microwave rectifying					
	(C) Microwave amplifying	(D)	Microwave oscillating					
5.	The gunn effect is also known as			1	1	2	1	
	(A) Transfer transient effect	(B)	Transient avalanche effect					
	(C) Auto electronic effect	(D)	Transferred electron effect					
6.	To prevent an IMPATT diode from	burni	ng, a constant bias source is used	1 1	1	2	1	
	to maintain at safe limit							
	(A) Average Voltage	(B)	Average Current					
	(C) Average bias Voltage	(D)	Average Resistance					
7.	Which of the following devices have	e nega	tive resistance?	1	1	2	1	
	(A) Vacuum diode		Tunnel diode					
	(C) Gas diode	(D)	TRAPATT diode					
8.	In order to achieve high current den	sity, a	compromise in is made	e <sup>1</sup>	1	2	1	
	in a TRAPATT diode							
	(A) Operating Frequency	(B)	Size					
	(C) Gain	(D)	No Compromise is made on any	/				
			parameters					

9.	One major disadvantage of BJTs over	·FET	Ts is that	1	1	3	1
			They have good noise figure				
	real Land and a contract of the contract of th		They do not have good noise				
10	TTI 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0		figure				
10	The frequency of operation of FET is		•	1	1	3	1
			Drain to source voltage				
	(C) Gate to source voltage	(D)	Effective area of FET				
11.	Production transistors commonly used	l for	microwave communications are	1	I	3	1
			MESFETs				
	(C) JFETs	(D)	MISFETs				
12	BJTs are suitable for RF applications	haca	use of	1	1	3	1
14.			Good Performance interms of	-	•	J	•
	(21) Tower Capacity	(D)	frequency				
	(C) Noise characteristics	(D)	Good Performance interms of				
	(c) Troise situate or issues	(1)	frequency power capacity and				
			noise characteristics				
12	HEMT used in the microwave circuit	:		1	1	4	1
13.	(4)		High Downer Association	1	Ţ	7	1
	(6) -		High Power Amplifier Low Noise Amplifier				
	·	(D)	Low Noise Amplifier				
14.	The channel charging delay in HEMT	is		1	1	4	1
	(A) Maximum at high current	(B)	Minimum at low current				
	densities		densities				
	(C) Minimum at high current	(D)					
	densities		densities				
15.	The optimum value of Lgd in HEMT i	is		1	1	4	1
	(A) 32 times that of the gate length		4.2 times that of the gate length				
	Lg		Lg				
	(C) 2.3 times that of the gate length	(D)	2.4 times that of the gate length				
	Lg		Lg				
16.	The method used for fabrication of Ga	As F	ET is	1	1	4	1
			Disposition				
			Conduction				
17.	management is prob	sobly	y one of the most suiting!	1	1	5	1
- / -	of the package design.	aury	one of the most critical aspects		•	5	•
		(B)	Thermal				
		` '	Computer Integrated				
18	The thermal conductivity of diamond i	ic		1	1	5	1
10.			40W/in°C		4	J	
		` '	40.06W/in°C				
	(-, 10.0111111	121	TO OUT WITH C				

19	effects result in poor RF performance with respect to things	1	1	5	1
	such as gain, efficiency and intermodulation distortion etc.				
	(A) Resistive (B) Deductive				
	(C) Reactive (D) Inductive				
20.	The most critical heat producing component for most RF systems is the stage	1	1	5	1
	(A) Frequency amplifier (B) Current amplifier				
	(C) Voltage amplifier (D) Power amplifier				
	$PART - B (5 \times 4 = 20 Marks)$				
	Answer ANY FIVE Questions	Marks	BL	CO	PO
21.	Describe the effect of doping profile on the capacitance of pn junctions.	4	2	1	1
22	W/h-4 i- 41i1	4	2	2	
22.	What is tunneling phenomenon?	4	2	2	1
23.	A TRAPATT diode has the following parameters.	4	3	2	4
	Doping Concentration $N_A = 2 \times 10^{15} \text{ cm}^{-3}$				
	Current density $J = 20kA/cm^2$				
	Calculate the avalanche zone velocity.				
24	Ctata Didiana Washing IIII	4	2	2	1
24.	State Ridley – Watkins Hilsun theory.	4	2	2	1
25.	Elucidate the Pinch – off voltage of JFET.	4	2	3	1
26.	Explain the figure of merit of RF power transistors.	4	2	4	1
27	Explore spreading resistance with relevant expressions.	4	2	5	1
	Explore spreading resistance with relevant expressions.				
	$PART - C (5 \times 12 = 60 Marks)$				
	Answer ALL Questions	Marks	BL	CO	PO
28. a.	Illustrate the working principle of varactor diode with neat schematic and	12	4	1	1
	give the applications.				
	(OR)				
b.	Examine the energy band diagram for an n-Ge-p-GaAs junction with	12	3	1	4
	relevant expressions.				
29 a	Illustrate the operational principle of an IMPATT diode and deduce its	12	3	2	1
27. u.	output power and efficiency.				-
	(OR)				
<b>b</b> .	Investigate the modes of operation for Gunn diodes with relevant	12	4	2	1
	characteristics.				
30 2	Describe in detail the principle of operation of MISFET with neat schematic	12	4	3	1
υ. a.	and V-I characteristics.			5	1

(OR)

b.	A typical n-channel Ga As M	ESFET has the following parameters	12	3	3	4
	Electron concentration	$N_d = 8 \times 10^{17} \text{ cm}^{-3}$				
	Channel height	$a = 0.1 \mu m$				
	Relative dielectric constant	$\varepsilon_{\rm r} = 13.1$				
	Channel length	$L = 14\mu m$				
	Channel width	$z = 36 \mu m$				
	Electron mobility	$\mu = 0.08 \text{m}^2/\text{Vs}$				
		$V_d = 5V$				
		$V_g = -2V$				
	Saturation drift velocity	$v_s = 2 \times 10^5 \text{ m/s}$				
		ge, velocity ratio and the saturation current at				
	$V_g = 0$					
		1			,	
31. a.	Elucidate the operational i	mechanism of HEMT and the operational	12	4	4	1
	characteristics.					
		(OR)	12	3	4	4
b.	A HEMT has the following p		12	5	•	
		$V_{th} = 0.13V$				
	Donor Concentration	$N_d = 2 \times 10^{24} \text{ m}^{-3}$				
	Schottky barrier potential	$ \phi_{\rm ms} = 0.8V $				
	GaAs bandgap	$E_{gg} = 1.43V$				
	Al GaAs bandgap	$E_{ga} = 1.8V$				
		d edge different between GaAs and Al GaAs				
	and the sensitivity of HEMT					
2.2	T	and the few Electronic exectors	12	4	5	
32. a.	Interpret the thermal resistan	ce networks for Electronic systems.				
		(OR)				
h	Investigate the technique	used to measure the fracture strength of	12	3	5	2
٥.	semiconductor diode.					

\* \* \* \* \*